A Complete Bibliography of Publications in *Technometrics* for the decade 1970–1979

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Title word cross-reference

[TC75a]. **Reflected** [Coh73]. **Regime** [Rif71, WB74]. **Regions** [Dun78b, Luc76, Obe77, LR78]. **Regression** [Ait74, ABA72, And74, Ano74f, Ano84, BC71, Bea70, BL74b, Ber78, Bro77, Coo77, Cro78, DM77, Dun78b, Far75, Far78, For72, Fra77, Gaf78, Gor76, Gre71, GWM76, Hah72, Hal70, Haw75, Hem75, Hil78, HJF78, Hoc72, HSL76, HK70a, HK70b, HK75, HR75, Hoo79, IC79, J.75d, KME71, LH70, LM72, LS71a, LSM72, Mar70, MK70, MS73, McK79, MHL74, MHL77a, MHL77b, NW77, NW79, NH72, NH73, Obe77, Par70, Par78a, PW72, Rah76, Sac76, SH79, SS71a, Sne77, SD75, SD77, TMB73, WGM74, WG79, Wio70, YF76, Zel72, DV79, Ell78, McC78a, For71, Fre75, Hah79]. **Regressions** [BC79b, DH74, Fur71, FW74, MT72, Rub76, SS71b]. **Regular** [Ber72b, Gue72, TS79, GH75]. **Reinhardt** [Hac78]. **Rejecting** [Ste72a]. **Related** [Ano72e, Ano73h, BD71, For73, J.79u, JS76, Wol77a]. **Relating** [MS73]. **Relations** [Haw75]. **Relationship** [All74, McL74b, NH72, NH73, Zel72]. **Relationships** [CH70, JH73a]. **Relative** [LR76, NW77]. **Relevant** [YC71]. **Reliability** [Bha73, BGH73, Bod70, Bri74, BWL78, CB75, CH70, DY70, EB78c, FB75, Gro71a, Gru71b, Gru71c, HBA71, Hei76, Her70, HM76b, J.78j, MG74, Pie73, Rea71, Sar71, Smi77, TBA70, TC75a, Var70, WK71, WG78, Whi70, Ziz78, J.77n, Kab74, Eas72, J.75f, J.77j]. **Remark** [Rea71]. **Remarks** [AvdL70, Nel75, SB72a]. **REML** [CS76]. **Renewal** [BGH73, HD70]. **Renyi** [Rog70c]. **Reordering** [BS72]. **repair** [Bha73]. **Repairing** [HM72]. **Replacement** [CH74, IS76, RR76, Sch71b, TC75b]. **Replacements** [IR77]. **Replication** [Gre71]. **Report** [Ale72, Ano74g, Com70, Com71]. **Representation** [Lac71a]. **Required** [SdV73]. **Requiring** [Dic74]. **Research** [Cha70a, Gle78, J.79n, Ger75, Gle77, J.77a, Lac72b]. **Residual** [LM72, MT72]. **Residuals** [BD72b, Dan78, DL70, GW75, JM79, Nel73, Sne71, Woo73]. **Resolution** [AT79, LS71b, SC71, SLM74]. **Response** [CP75, CO75, HM72, HS73, Luc76, MB78b, MC73, ML75, Roq76, Sne72b, Sne75a, Nay72, Man73]. **Responses** [Sta79]. **Restricted** [AF76, CS76, Joh70a, SN77, Wat74]. **Restrictions** [Kal75]. **Results** [Bai73, BB79, Bis79, DM78, Dun78a, EB73, EB74, Hol75, LL78, McL72, Nel72a, Weg74, YC71]. **Review** [Add72, Add79, And70, And75, Ano71f, Ano74e, Bak74, Ban73, Bed74, Bel70, Ben76, Ber72b, Ber73, Bha72, Bis72a, Bis72b, Boa79b, Bon76a, Bon76b, Bon77, Bow77, Bow78, Boy74, Bri73a, Buc73, Cam77, Car77a, Car77b, Car74, Cas76, Cha75a, Cha75b, Che71, Cle72a, Con74, Coo72, Cor71, Cor73, Cra74, Cro78, Cru78a, Cru78b, Dal77, Dav70, Dav77, Dil71, Doo72, Dra79, Dud79, Dun72, Dun77a, Dun77b, Dye74, Dyk76, Eas72, Ehr77, Ens76, Ens77, Ens78, Eri72, Fed74a, Fed77, Fie73, Fin75, Fle76, For71, For73, FW72, Fre73a, Fre73b, Fre73c, Fre74b, Fre74a, Fre75, Gen77, Geo72, Ger75, Gib74, Gie74, Gil74, Gle78, Gle77, Gol74, Goo75, Goo76, Gor76, Gou73, Gow72, Gra72, Gri73, Gro77, Gru71a, Gua71, Hac78, Hac79, Hah79, Hal77b]. **Review** [Ham75, Han73, Har77, Har70, Har75, Har72, Hay73, Hea78, Hei76, Hei78,

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